## Notice of References Cited 10/088,868 Reexamination LENZ ET AL. Examiner Kartic Padmanabhan Reexamination LENZ ET AL. Page 1 of 1

Application/Control No.

Applicant(s)/Patent Under

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name .	Classification
*	Α	US-5,824,503	10-1998	Kurome et al.	435/69.1
*	В	US-5,300,490	04-1994	Kunihiro et al.	514/8
*	С	US-6,338,951	01-2002	Soppet et al.	435/69.1
	D	US-			
	Ε	US-			
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			· · · · · · · · · · · · · · · · · · ·
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	,				
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-	Р					
	Q					
	R					
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## **NON-PATENT DOCUMENTS**

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	<b>V</b>	
	w	
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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